

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/849,857	ITAYA ET AL.	
Examiner	Art Unit	
Jan M. Ludlow	1743	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
updated search	7/28/2005	JML	
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